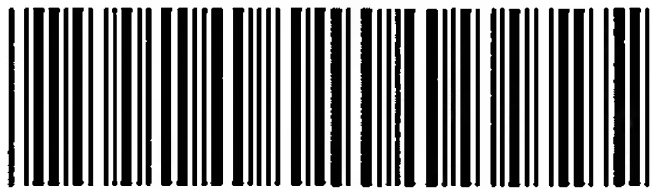


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/645,617	SHIMAMURA ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Ben Lewis	1745	

SEARCHED			
Class	Subclass	Date	Examiner
429	162	6/6/2006	BL
429	163	6/6/2006	BL
429	171	6/6/2006	BL
429	185	6/6/2006	BL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	6/6/2006	BL